## 0.1 Ssd: intrinsic resolution

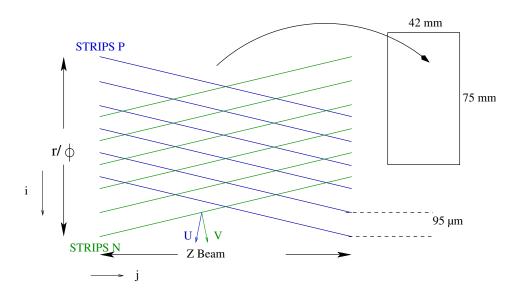


Fig. 1 – Orientation of Strips P and N in a wafer

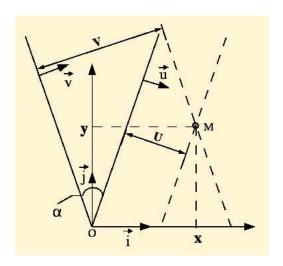


Fig. 2 – Relation between the local frame to the wafer (strips) and global coordinates :  $r\phi$  and Z

 $(\overrightarrow{U},\overrightarrow{V})$  are in the strips frame whereas  $(\overrightarrow{i},\overrightarrow{j})$  are are in the global frame with  $\overrightarrow{i}$  along  $r\phi$  and  $\overrightarrow{j}$  along Z.

 $\alpha$  is the stereo angle between strips of P-side and strips of N-side and its value is  $\alpha=35$  mrad.

$$\left\{ \begin{array}{l} \overrightarrow{U} = cos\frac{\alpha}{2}\overrightarrow{i'} - sin\frac{\alpha}{2}\overrightarrow{j'} \\ \overrightarrow{V} = cos\frac{\alpha}{2}\overrightarrow{i'} + sin\frac{\alpha}{2}\overrightarrow{j'} \end{array} \right.$$

Then in the global coordinates, we get:

$$\begin{cases} r\phi = \frac{\overrightarrow{U} + \overrightarrow{V}}{\frac{2\cos\frac{\alpha}{2}}{2}} \\ Z = \frac{\overrightarrow{U} - \overrightarrow{V}}{\frac{2\sin\frac{\alpha}{2}}{2}} \end{cases}$$

For the resolution in  $r\phi$  and Z, and by using the errors propagation :

$$\begin{cases} \sigma_{r\phi} = \frac{\sigma U \oplus \sigma V}{2cos\frac{\alpha}{2}} \\ \sigma_{Z} = \frac{\sigma U \oplus \sigma V}{2sin\frac{\alpha}{2}} \end{cases}$$

$$\begin{cases} \sigma_{r\phi} = \frac{\sigma_{U}}{\sqrt{2}cos\frac{\alpha}{2}}(a) \\ \sigma_{Z} = \frac{\sigma_{U}}{\sqrt{2}sin\frac{\alpha}{2}}(b) \end{cases}$$

As the strip pitch is  $95\mu m$ :

$$\sigma_U \simeq = \frac{95}{\sqrt{12}} \simeq 27 \mu m \tag{1}$$

so when we report  $\sigma_U$  in (a) and (b), we have :

$$\begin{cases} \sigma_{r\phi} \simeq 20\mu m \\ \sigma_Z \simeq 1000\mu m \end{cases}$$

But people were not using  $\sigma_U=27\mu$  m but results from beam test which gave  $\sigma_U\simeq 21\mu{\rm m}$ .